

Refine Search

Search Results -

Terms	Documents
L22 and (DUT or sample or specimen or test chip)	2525

Database:

US Pre-Grant Publication Full-Text Database
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 US OCR Full-Text Database
 EPO Abstracts Database
 JPO Abstracts Database
 Derwent World Patents Index
 IBM Technical Disclosure Bulletins

Search:

L26 and (test \$3 near chamber or test\$3
 near handler or test near platform or
 test near probe or prob\$3 near stage or

Search History

DATE: Monday, June 18, 2007 [Purge Queries](#) [Printable Copy](#) [Create Case](#)

<u>Set</u> <u>Name</u> <u>Query</u> side by side	<u>Hit</u> <u>Count</u>	<u>Set</u> <u>Name</u> result set
<i>DB=PGPB,USPT,USOC,EPAB,JPAB; PLUR=YES; OP=ADJ</i>		
<u>L26</u> L22 and (DUT or sample or specimen or test chip)	2525	<u>L26</u>
<u>L25</u> L24 and (heat\$3 near air or heat\$3 near fluid or cool\$3 near air or cool\$3 near fluid)	32	<u>L25</u>
<u>L24</u> L22 and (central near opening or central near aperture)	231	<u>L24</u>
<u>L23</u> L22 and (circular near sample near mount\$3 or circular near sample near arrangement or circular near sample near positioning)	0	<u>L23</u>
<u>L22</u> (374/33,31,29,39,10,12,50,57,11;324/760,158.1,763,538)![CCLS]	10233	<u>L22</u>
<i>DB=PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD; PLUR=YES; OP=ADJ</i>		
<u>L21</u> 374/33	174	<u>L21</u>
<u>L20</u> L16 and (thermal near test\$3 apparatus or thermal near test\$3 device or thermal near test\$3 chamber or thermal near test\$3 platform or thermal\$2 near prob\$3 stage or wafer near prob\$3 stage or semiconductor near prob\$3 stage)	29	<u>L20</u>
<u>L19</u> L17 and (specimen near mount\$3 or specimen near arrangement or spesimen	4	<u>L19</u>

	near position\$3 or specimen near platrform or specimen near arrang\$3)		
<u>L18</u>	L17 and (sample near mount\$3 or sample near arrangement or sample near position\$3 or sample near platrform or sample near arrang\$3)	17	<u>L18</u>
<u>L17</u>	L16 and (thermal\$2 near test\$3 or thermal near signature\$1)	242	<u>L17</u>
<u>L16</u>	374/\$.ccls.	29640	<u>L16</u>
<u>L15</u>	(circular\$2 near5 test samples) and (thermal\$2 near test\$3)	0	<u>L15</u>
<u>L14</u>	circular\$2 near5 test samples	148	<u>L14</u>
<u>L13</u>	circumferential\$2 near5 test samples	7	<u>L13</u>
<u>L12</u>	circumferential\$2 near5 samples	1047	<u>L12</u>
<u>L11</u>	circumferentialy near arrang\$4 near samples	0	<u>L11</u>
<u>L10</u>	circular near arrang\$4 tests samples	0	<u>L10</u>
<u>L9</u>	circular sample mount\$3 or circular sample holder or circular sample arrangement or circular sample position\$3	49	<u>L9</u>
<u>L8</u>	L7 and (IC or chips or samples or specimen)	69	<u>L8</u>
<u>L7</u>	L6 and (heat\$3 or cool\$3)	90	<u>L7</u>
<u>L6</u>	L2 and (circular arrangement or circular mount\$3 or circular position\$3 or central opening or central aperture or circumferential mount\$3 or circumferential position\$3 or circumferential arrangement)	204	<u>L6</u>
<u>L5</u>	L4 and (circular)	31	<u>L5</u>
<u>L4</u>	L3 and (test\$3 near chamber)	162	<u>L4</u>
<u>L3</u>	L2 and (test\$3)	4873	<u>L3</u>
<u>L2</u>	324/158.1	5716	<u>L2</u>
	<i>DB=USPT; PLUR=YES; OP=ADJ</i>		
<u>L1</u>	6040691.pn.	1	<u>L1</u>

END OF SEARCH HISTORY

Searches for User *gverbitsky* (Count = 49278)

Queries 49229 through 49278.

Find			
Latest	Prev	Next	Oldest
Edit	Help	Cancel	

S #	Updt	Database	Query
<u>S49278</u>	<u>U</u>	PGPB,USPT,USOC,EPAB,JPAB	((374/33,31,29,39,10,12,50,57,11;324/76 [CCLS] and (DUT or sample or specime \$3 near chamber or test\$3 near handler o test near probe or prob\$3 near stage or pi or sample near puck or sample near table or sample near support or specimen near
<u>S49277</u>	<u>U</u>	PGPB,USPT,USOC,EPAB,JPAB	((374/33,31,29,39,10,12,50,57,11;324/76 [CCLS] and (DUT or sample or specime \$3 near chamber or test\$3 near handler o test near probe or prob\$3 near stage or pi or sample near puck or sample near table or sample near support or specimen near
<u>S49276</u>	<u>U</u>	PGPB,USPT,USOC,EPAB,JPAB	((374/33,31,29,39,10,12,50,57,11;324/76 [CCLS] and (DUT or sample or specime \$3 near chamber or test\$3 near handler o test near probe or prob\$3 near stage or pi or sample near puck)
<u>S49275</u>	<u>U</u>	PGPB,USPT,USOC,EPAB,JPAB	((374/33,31,29,39,10,12,50,57,11;324/76 [CCLS] and (DUT or sample or specime \$3 near chamber or test\$3 near handler o test near probe or prob\$3 near stage or pi or sample near puck)
<u>S49274</u>	<u>U</u>	PGPB,USPT,USOC,EPAB,JPAB	((374/33,31,29,39,10,12,50,57,11;324/76 [CCLS] and (DUT or sample or specime \$3 near chamber or test\$3 near handler o test near probe or prob\$3 near stage or pi
<u>S49273</u>	<u>U</u>	PGPB,USPT,USOC,EPAB,JPAB	((374/33,31,29,39,10,12,50,57,11;324/76 [CCLS] and (DUT or sample or specime \$3 near chamber or test\$3 near handler o test near probe or prob\$3 near stage or pi
<u>S49272</u>	<u>U</u>	PGPB,USPT,USOC,EPAB,JPAB	((374/33,31,29,39,10,12,50,57,11;324/76 [CCLS] and (DUT or sample or specime \$3 near chamber or test\$3 near handler o test near probe or prob\$3 near stage or pi
<u>S49271</u>	<u>U</u>	PGPB,USPT,USOC,EPAB,JPAB	((374/33,31,29,39,10,12,50,57,11;324/76

<u>S49270</u>	<u>U</u>	PGPB,USPT,USOC,EPAB,JPAB	[CCLS] and (DUT or sample or specime \$3 near chamber or test\$3 near handler o test near probe or prob\$3 near stage or pi ((374/33,31,29,39,10,12,50,57,11;324/76 [CCLS] and (DUT or sample or specime \$3 near chamber or test\$3 near handler o test near probe or prob\$3 near stage or pi ((374/33,31,29,39,10,12,50,57,11;324/76 [CCLS] and (DUT or sample or specime \$3 near chamber or test\$3 near handler o test near probe or prob\$3 near stage or pi ((374/33,31,29,39,10,12,50,57,11;324/76 [CCLS]) and (DUT or sample or specim
<u>S49269</u>	<u>U</u>	PGPB,USPT,USOC,EPAB,JPAB	((374/33,31,29,39,10,12,50,57,11;324/76 [CCLS] and (DUT or sample or specime \$3 near chamber or test\$3 near handler o test near probe or prob\$3 near stage or pi ((374/33,31,29,39,10,12,50,57,11;324/76 [CCLS] and (DUT or sample or specime \$3 near chamber or test\$3 near handler o test near probe or prob\$3 near stage or pi ((374/33,31,29,39,10,12,50,57,11;324/76 [CCLS]) and (DUT or sample or specim
<u>S49268</u>	<u>U</u>	PGPB,USPT,USOC,EPAB,JPAB	((374/33,31,29,39,10,12,50,57,11;324/76 [CCLS] and (DUT or sample or specime \$3 near chamber or test\$3 near handler o test near probe or prob\$3 near stage or pi ((374/33,31,29,39,10,12,50,57,11;324/76 [CCLS]) and (DUT or sample or specim
<u>S49267</u>	<u>U</u>	PGPB,USPT,USOC,EPAB,JPAB	((374/33,31,29,39,10,12,50,57,11;324/76 [CCLS]) and (DUT or sample or specim
<u>S49266</u>	<u>U</u>	PGPB,USPT,USOC,EPAB,JPAB	((374/33,31,29,39,10,12,50,57,11;324/76 [CCLS] and (central near opening or cen (heat\$3 near air or heat\$3 near fluid or c near fluid)
<u>S49265</u>	<u>U</u>	PGPB,USPT,USOC,EPAB,JPAB	((374/33,31,29,39,10,12,50,57,11;324/76 [CCLS]) and (central near opening or ce
<u>S49264</u>	<u>U</u>	PGPB,USPT,USOC,EPAB,JPAB	((374/33,31,29,39,10,12,50,57,11;324/76 [CCLS]) and (circular near sample near sample near arrangement or circular near positioning)
<u>S49263</u>	<u>U</u>	PGPB,USPT,USOC,EPAB,JPAB	(374/33,31,29,39,10,12,50,57,11;324/76 [CCLS]
<u>S49262</u>	<u>U</u>	PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD	374/33
<u>S49261</u>	<u>U</u>	PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD	(374/\$.ccls.) and (thermal near test\$3 ap test\$3 device or thermal near test\$3 chan test\$3 platform or thermal\$2 near prob\$2 prob\$3 stage or semiconductor near prob
<u>S49260</u>	<u>U</u>	PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD	(374/\$.ccls. and (thermal\$2 near test\$3 o signature\$1)) and (specimen near mount arrangement or spesimen near position\$2 platrform or specimen near arrang\$3)
<u>S49259</u>	<u>U</u>	PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD	(374/\$.ccls. and (thermal\$2 near test\$3 o signature\$1)) and (sample near mount\$2 arrangement or sample near position\$3 o or sample near arrang\$3)
<u>S49258</u>	<u>U</u>	PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD	(374/\$.ccls.) and (thermal\$2 near test\$3

signature\$1)

- S49257 U PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD 374/\$.ccls.
- S49256 U PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD (circular\$2 near5 test samples) and (then
- S49255 U PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD circular\$2 near5 test samples
- S49254 U PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD circumferential\$2 near5 test samples
- S49253 U PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD circumferential\$2 near5 samples
- S49252 U PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD circumferentially near arrang\$4 near sam
- S49251 U PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD circular near arrang\$4 tests samples
- S49250 U PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD circular sample mount\$3 or circular sam
sample arrangement or circular sample p
- S49249 U PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD (324/158.1 and (circular arrangement or
circular position\$3 or central opening or
circumferential mount\$3 or circumferent
circumferential arrangement) and (heat\$
chips or samples or specimen)
- S49248 U PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD (324/158.1 and (circular arrangement or
circular position\$3 or central opening or
circumferential mount\$3 or circumferent
circumferential arrangement)) and (heat
- S49247 U PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD (324/158.1) and (circular arrangement o
circular position\$3 or central opening or
circumferential mount\$3 or circumferent
circumferential arrangement)
- S49246 U PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD (324/158.1) and (circular arrangement o
circular position\$3 or central opening or
circumferential mount\$3 or circumferent
circumferential arrangement)
- S49245 U PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD (324/158.1) and (circular arrangement o
circular position\$3 or central opening or
circumferential mount\$3 or circumferent
circumferential arrangement)
- S49244 U PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD (324/158.1 and (test\$3) and (test\$3 near